

International **IR** Rectifier **HEXFET® POWER MOSFET**

Provisional Data Sheet No. PD 9.1291B

IRFY430CM

N-CHANNEL

500 Volt, 1.5Ω HEXFET

HEXFET technology is the key to International Rectifier's advanced line of power MOSFET transistors. The efficient geometry design achieves very low on-state resistance combined with high transconductance.

HEXFET transistors also feature all of the well-established advantages of MOSFETs, such as voltage control, very fast switching, ease of paralleling and electrical parameter temperature stability. They are well-suited for applications such as switching power supplies, motor controls, inverters, choppers, audio amplifiers, high energy pulse circuits, and virtually any application where high reliability is required.

The HEXFET transistor's totally isolated package eliminates the need for additional isolating material between the device and the heatsink. This improves thermal efficiency and reduces drain capacitance.

Product Summary

Part Number	BVDSS	RDS(on)	ID
IRFY430CM	500V	1.5Ω	4.5A

Features

- Hermetically Sealed
- Electrically Isolated
- Simple Drive Requirements
- Ease of Paralleling
- Ceramic Eyelets

Absolute Maximum Ratings

	Parameter	IRFY430CM	Units
ID @ VGS=10V, TC = 25°C	Continuous Drain Current	4.5	A
ID @ VGS=10V, TC = 100°C	Continuous Drain Current	2.8	
IDM	Pulsed Drain Current ①	18	
PD @ TC = 25°C	Max. Power Dissipation	75	W
	Linear Derating Factor	0.6	W/K⑤
VGS	Gate-to-Source Voltage	±20	V
EAS	Single Pulse Avalanche Energy ②	280	mJ
IAR	Avalanche Current ①	4.5	A
EAR	Repetitive Avalanche Energy ①	7.5	mJ
dv/dt	Peak Diode Recovery dv/dt ③	3.5	V/ns
TJ	Operating Junction	-55 to 150	
Tstg	Storage Temperature Range		°C
	Lead Temperature	300 (0.063 in (1.6mm) from case for 10 sec)	°C
	Weight	4.3 (typical)	g

IRFY430CM Device

Electrical Characteristics @ $T_J = 25^\circ\text{C}$ (Unless Otherwise Specified)

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
BV_{DSS}	Drain-to-Source Breakdown Voltage	500	—	—	V	$\text{V}_{\text{GS}} = 0\text{V}, \text{I}_D = 1.0\text{mA}$
$\Delta \text{BV}_{\text{DSS}}/\Delta T_J$	Temperature Coefficient of Breakdown Voltage	—	0.78	—	$\text{V}/^\circ\text{C}$	Reference to 25°C , $\text{I}_D = 1.0\text{mA}$
$\text{R}_{\text{DS(on)}}$	Static Drain-to-Source On-State Resistance	—	—	1.5	Ω	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 2.8\text{A}$ ④
	On-State Resistance	—	—	1.8		$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 4.5\text{A}$
$\text{V}_{\text{GS(th)}}$	Gate Threshold Voltage	2.0	—	4.0	V	$\text{V}_{\text{DS}} = \text{V}_{\text{GS}}, \text{I}_D = 250\mu\text{A}$
g_{fs}	Forward Transconductance	1.5	—	—	$\text{S} (\text{A})$	$\text{V}_{\text{DS}} \geq 15\text{V}, \text{I}_{\text{DS}} = 2.8\text{A}$ ④
I_{DSS}	Zero Gate Voltage Drain Current	—	—	25	μA	$\text{V}_{\text{DS}} = 0.8 \times \text{max. rating}, \text{V}_{\text{GS}} = 0\text{V}$
		—	—	250		$\text{V}_{\text{DS}} = 0.8 \times \text{max. rating}$ $\text{V}_{\text{GS}} = 0\text{V}, T_J = 25^\circ\text{C}$
I_{GSS}	Gate-to-Source Leakage Forward	—	—	100	nA	$\text{V}_{\text{GS}} = 20\text{V}$
I_{GSS}	Gate-to-Source Leakage Reverse	—	—	-100		$\text{V}_{\text{GS}} = -20\text{V}$
Q_g	Total Gate Charge	19.8	—	29.5	nC	$\text{V}_{\text{GS}} = 10\text{V}, \text{I}_D = 4.5\text{A}$
Q_{gs}	Gate-to-Source Charge	2.2	—	4.6		$\text{V}_{\text{DS}} = \text{Max. Rating} \times 0.5$
Q_{gd}	Gate-to-Drain ('Miller') Charge	5.5	—	19.7		see figures 5 and 13
$\text{t}_{\text{d(on)}}$	Turn-On Delay Time	—	—	35		
t_r	Rise Time	—	—	30	ns	$\text{V}_{\text{DD}} = 250\text{V}, \text{I}_D = 4.5\text{A}, \text{R}_G = 7.5, \text{V}_{\text{GS}} = 10\text{V}$
$\text{t}_{\text{d(off)}}$	Turn-Off Delay Time	—	—	55		
t_f	Fall Time	—	—	30		see figure 10
L-D	Internal Drain Inductance	—	8.7	—	nH	Measured from the drain lead, 6mm (0.25 in.) from package to center of die.
L-S	Internal Source Inductance	—	8.7	—		Modified MOSFET symbol showing the internal inductances. 
C_{iss}	Input Capacitance	—	6.0	—	pF	$\text{V}_{\text{GS}} = 0\text{V}, \text{V}_{\text{DS}} = 25\text{V}$
C_{oss}	Output Capacitance	—	135	—		$f = 1.0\text{MHz}$.
Crss	Reverse Transfer Capacitance	—	65	—		see figure 5

Source-Drain Diode Ratings and Characteristics

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
I_S	Continuous Source Current (Body Diode)	—	—	4.5	A	Modified MOSFET symbol showing the integral reverse p-n junction rectifier. 
I_{SM}	Pulse Source Current (Body Diode) ④	—	—	18		
V_{SD}	Diode Forward Voltage	—	—	1.4	V	$T_J = 25^\circ\text{C}, \text{I}_S = 4.5\text{A}, \text{V}_{\text{GS}} = 0\text{V}$ ④
t_{rr}	Reverse Recovery Time	—	—	900	ns	$\text{T}_J = 25^\circ\text{C}, \text{I}_F = 4.5\text{A}, \text{di/dt} \leq 100 \text{ A}/\mu\text{s}$
Q_{RR}	Reverse Recovery Charge	—	—	7.0	μC	$\text{V}_{\text{DD}} \leq 50\text{V}$ ④
t_{on}	Forward Turn-On Time	Intrinsic turn-on time is negligible. Turn-on speed is substantially controlled by $\text{L}_S + \text{L}_D$.				

Thermal Resistance

	Parameter	Min.	Typ.	Max.	Units	Test Conditions
R_{thJC}	Junction-to-Case	—	—	1.67	K/W⑤	
R_{thJA}	Junction-to-Ambient	—	—	80		Typical socket mount
R_{thCS}	Case-to-Sink	—	0.21	—		Mounting surface flat, smooth

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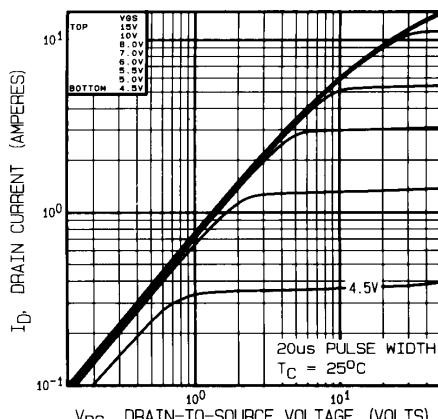


Fig. 1 — Typical Output Characteristics
 $T_C = 25^\circ\text{C}$

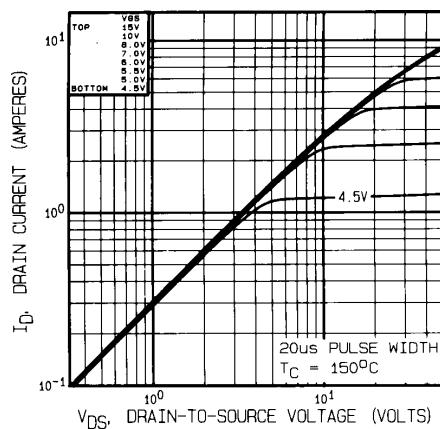


Fig. 2 — Typical Output Characteristics
 $T_C = 150^\circ\text{C}$

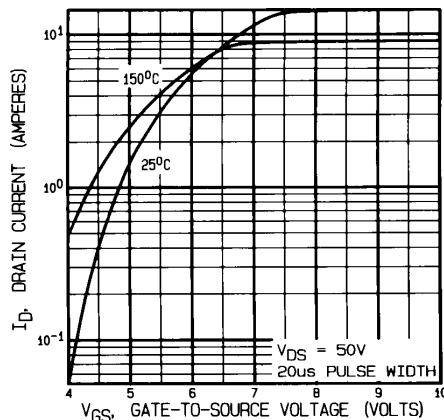


Fig. 3 — Typical Transfer Characteristics

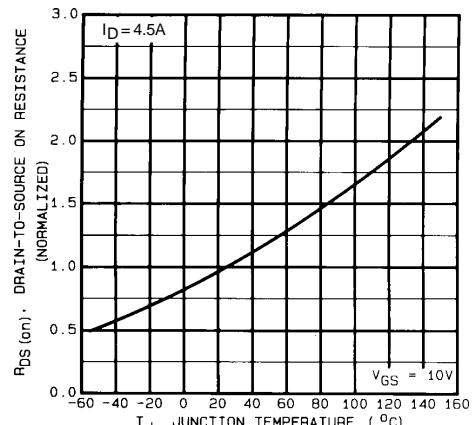


Fig. 4 — Normalized On-Resistance Vs. Temperature

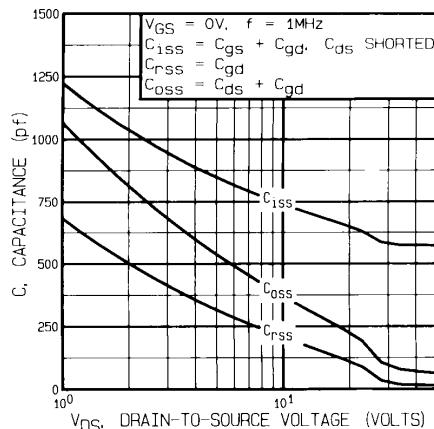


Fig. 5 — Typical Capacitance Vs. Drain-to-Source Voltage

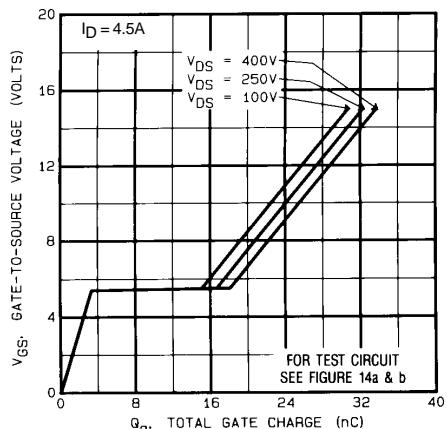


Fig. 6 — Typical Gate Charge Vs. Gate-to-Source Voltage

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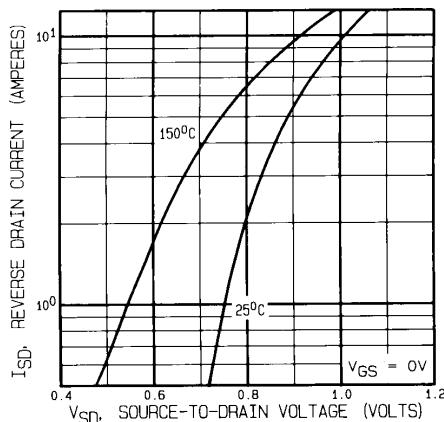


Fig. 7 — Typical Source-to-Drain Diode Forward Voltage

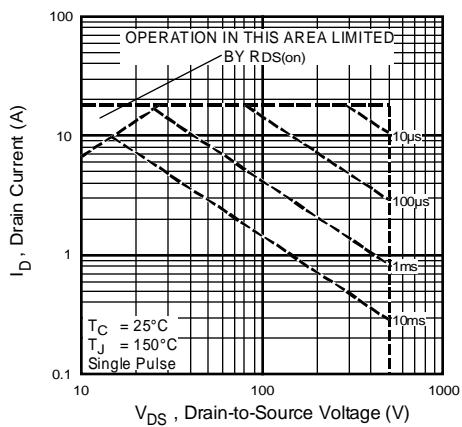


Fig. 8 — Maximum Safe Operating Area

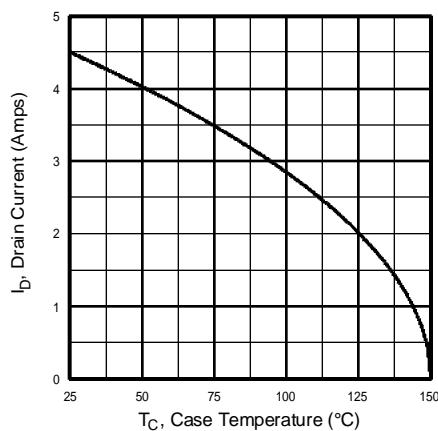


Fig. 9 — Maximum Drain Current Vs. Case Temperature

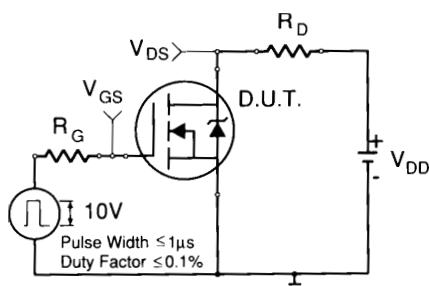


Fig. 10a — Switching Time Test Circuit

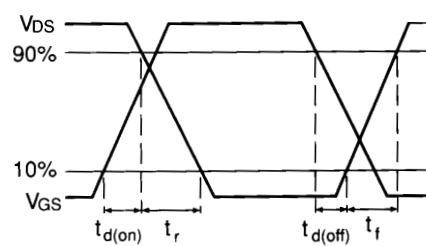


Fig. 10b — Switching Time Waveforms

IRFY430CM Device

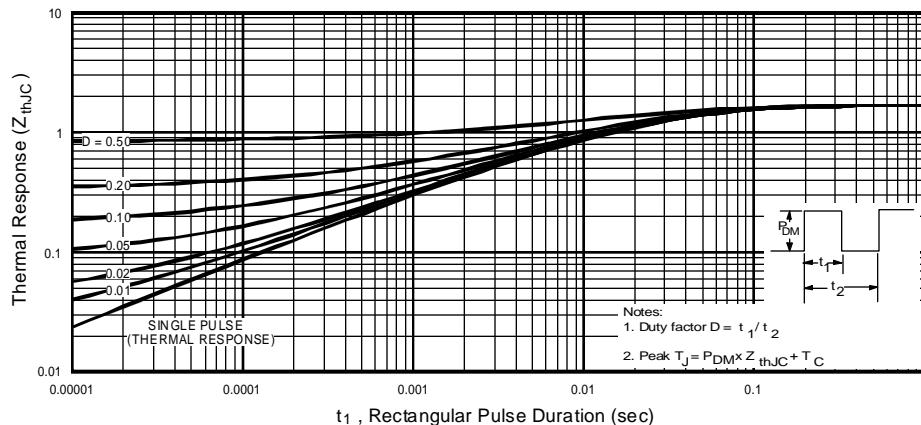


Fig. 11 — Maximum Effective Transient Thermal Impedance, Junction-to-Case Vs. Pulse Duration

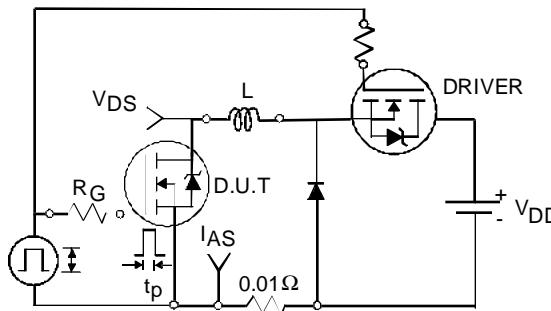


Fig. 12a — Unclamped Inductive Test Circuit

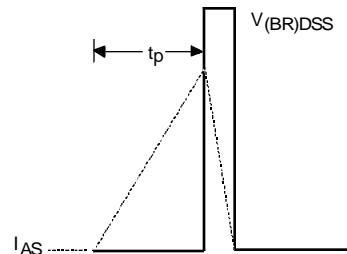


Fig. 12b — Unclamped Inductive Waveforms

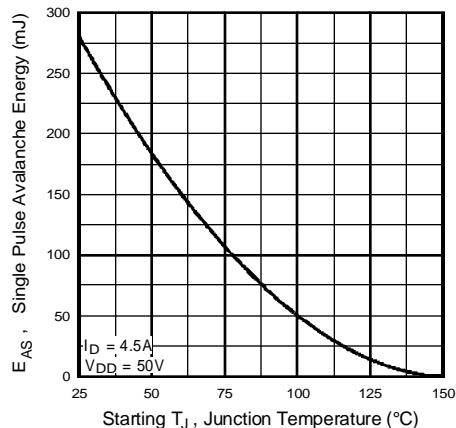


Fig. 12c — Max. Avalanche Energy vs. Current

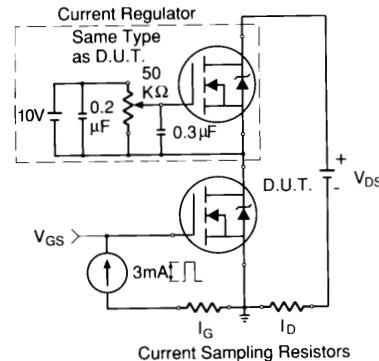
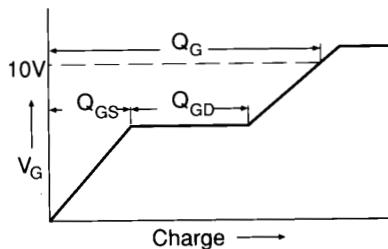


Fig. 13a — Gate Charge Test Circuit

IRFY430CM Device

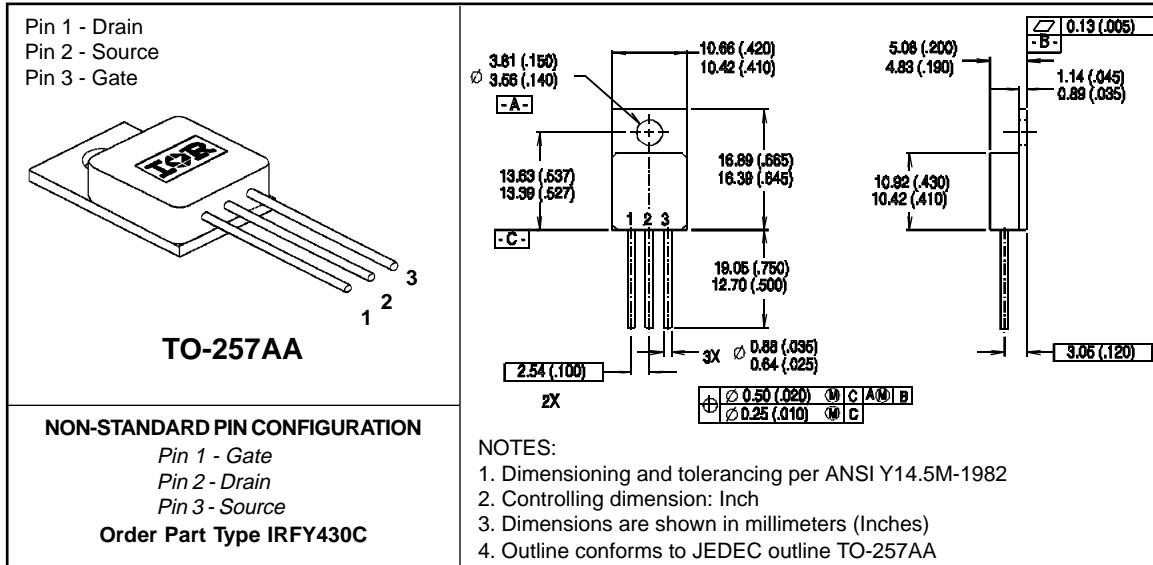


Notes:

- ① Repetitive Rating; Pulse width limited by maximum junction temperature (see figure 11).
- ② @ VDD = 50V, Starting TJ = 25°C,
EAS = $[0.5 * L * (I_L^2) * [BVDSS/(BVDSS-VDD)]]$
Peak IL = 4.5A, VGS = 10V, 25 ≤ RG ≤ 200Ω (figure 12)
- ③ ISD ≤ 4.5A, di/dt ≤ 75A/μs, VDD ≤ BVDSS, TJ ≤ 150°C
- ④ Pulse width ≤ 300 μs; Duty Cycle ≤ 2%
- ⑤ K/W = °C/W W/K = W/°C

Fig. 13b — Basic Gate Charge Waveform

Case Outline and Dimensions — TO-257AA



CAUTION

BERYLЛИA WARNING PER MIL-PRF-19500

Packages containing beryllia shall not be ground, sandblasted, machined or have other operations performed on them which will produce beryllia or beryllium dust. Furthermore, beryllium oxide packages shall not be placed in acids that will produce fumes containing beryllium.

International
IR Rectifier

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